Date Created : **2007/06/21**
Date Issued On : **2007/09/27**
PCN# : **Q3073404**

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

Updated process quality documentation, such as FMEAs and Control Plans, are available for viewing upon request.

If you have any questions concerning this change, please contact:

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Phone:

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Implementation of change:
Expected 1st Device Shipment Date: 2007/11/15

Earliest Year/Work Week of Changed Product: 0746

Change Type Description: Lead Frame Dimensions (Internal and External)

Description of Change (From): Current dual leadframe (433086, 436489, 422170, 422162, 427732)

Description of Change (To): New matrix leadframe (436895Q, 436896Q, 436897Q, 436898Q, 436899Q)

Reason for Change : To set up and qualify QSOP matrix line as an alternative and an eventual replacement for the existing line.

Qual/REL Plan Numbers : Q20060297

This is to qualify Carsem to use Matrix Leadframe for 16L/24L/28L QSOP packages.

Qualification :

All the reliability tests as defined in Q20060297 qualification plan completed with no failure. Therefore, Carsem, QSOP packages with Matrix Leadframe is qualified.

Results/Discussion

Test: (Autoclave)			
Lot	Device	96-HOURS	Failure Code
Q20060297AAACLV	FAN5236QSCX	0/77	
Q20060297ABACLV	FAN5236QSCX	0/77	
Q20060297ACACLV	FAN5236QSCX	0/77	
Test: (Gate Leakage Negative)			

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Lot	Device	Results	Failure Code
Q20060297AAGATE-	FAN5236QSCX	0/3	
Q20060297ABGATE-	FAN5236QSCX	0/3	
Q20060297ACGATE-	FAN5236QSCX	0/3	

Test: (Gate Leakage Positive)

Lot	Device	Results	Failure Code
Q20060297AAGATE+	FAN5236QSCX	0/3	
Q20060297ABGATE+	FAN5236QSCX	0/3	
Q20060297ACGATE+	FAN5236QSCX	0/3	

Test: (High Temperature Storage Life)

Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20060297AAHTSL	FAN5236QSCX	0/77			
			0/77		
				0/77	
Q20060297ABHTSL		0/77			
			0/77		
				0/77	
Q20060297ACHTSL		0/77			
			0/77		
				0/77	

Test: (Temperature Humidity Biased Test)

Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20060297AATHBT		0/77			
			0/77		
				0/77	

Test: -65C, 150C (Temperature Cycle)

Lot	Device	100-CYCLES	500-CYCLES	Failure Code
Q20060297AATMCL1	FAN5236QSCX	0/77		
Q20060297AATMCL1	FAN5236QSCX		0/77	
Q20060297ABTMCL1	FAN5236QSCX	0/77		
Q20060297ABTMCL1	FAN5236QSCX		0/77	
Q20060297ACTMCL1	FAN5236QSCX	0/77		
Q20060297ACTMCL1	FAN5236QSCX		0/77	

Test: MSL(2), PKG(Small), PeakTemp(260c), Cycles(3) (Precondition)

Lot	Device	Results	Failure Code
Q20060297AAPCNL2A	FAN5236QSCX	0/231	
Q20060297ABPCNL2A	FAN5236QSCX	0/154	
Q20060297ACPCNL2A	FAN5236QSCX	0/154	

Product Id Description :

Affected FSIDs :

FAN5236QSCX		

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